


<b>Search Notes</b> 	<b>Application/Control No.</b> 10792073	<b>Applicant(s)/Patent Under Reexamination</b> CHENG, HUI
	<b>Examiner</b> Radkiewicz, Jared W	<b>Art Unit</b> 2609

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	2934	2/6/2007	JWR

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
382 Keyword limited	2/6/2007	JWR
348 Keyword limited	2/6/2007	JWR

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>